


Search Notes 	Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/629,624		SHUTOH ET AL.	
	Examiner		Art Unit	
	Anthony Fick		1753	

SEARCHED			
Class	Subclass	Date	Examiner
136	203	1/9/2007	ADF
136	200-242	1/9/2007	ADF
<i>Updated &</i>		<i>8/16/07</i>	<i>ADF</i>

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See EAST search history	1/9/2007	ADF
Inventor search	1/9/2007	ADF
Consulted with Nam Nguyen	1/9/2007	ADF
Google scholar search for inventor and keywords	1/9/2007	ADF